

List of Patents and Publications for
Applicant's Information Disclosure Statement

APPLICANT: Trevathan, M.

(Use several sheets if necessary)

FILING DATE: Herewith

GROUP:

Reference Designation

US PATENT DOCUMENTS

Examiner Initials	Document Number	Date	Name	Class/Subclass	Filing Date (If. Appr.)
YEE	AA 6,163,773	12/19/00	Kishi	706/16	05/05/98
YEE	AB 6,006,003	12/21/99	Heisch	395/709 717/158	08/15/94
YEE	AC 5,881,231	3/09/99	Takagi et al.	395/200.42 709/212	03/07/96
YEE	AD 5,873,100	02/16/99	Adams et al.	707/204	12/20/96
YEE	AE 5,727,129	03/10/98	Barrett et al.	395/12 706/110	06/04/96
YEE	AF 5,497,477	03/05/96	Trull	395/480 711/133	03/07/94
YEE	AG 6,128,701	10/03/00	Malcolm, et al.	711/133	10/28/97
YEE	AH 6,125,394	09/26/00	Rabinovich	709/226	06/06/97
YEE	AI 5,043,885	08/27/91	Robinson	364/200 711/133	08/08/89

FOREIGN PATENT DOCUMENTS

	Document Number	Date	Country	Class/Subclass	Translation Yes No
YEE	AJ 11053244A	02/26/99	Japan	G06F12/00	X
YEE	AK 2050236	02/20/90	Japan	G06F12/08	X

OTHER ART (Including Author, Title, Data, Pertinent Pages, etc.)

- YEE Reedy, M. et al. "Exp1: a Comparison Between a Simple Adaptive Caching Agent Using Document Life Histories and Existing Cache Techniques", Computer Networks and ISDN Systems, vol. 30, nos. 22-23, pp. 214-58, 25 November 1998
2149-2153
- YEE Serpanos, D. N. et al. "Caching Web Objects Using Zipf's Law", Multimedia Storage and Archiving Systems III, Proceedings of SPIE (Conference), Boston, Nov. 2-4, 1998
Proceedings of SPIE, vol. 3527, pp. 320-26
- YEE Zhong, Su et al. "WhatNext: A Prediction System for Web Requests Using N-Gram Sequence Models" International Conference on Web Information Systems Engineering, Hong Kong, vol. 1, pp. 214-21, June 19-21, 2000 Proceedings
- YEE Laird, P. et al. "Discrete sequence Prediction and its Application", Machine Learning, vol. 15 issue: 1, pp. 43-68, April 1994

Examiner

Yamir Encarnación

Date Considered

3/27/03

Examiner: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.